

Search Notes

Application/Control No.

10/591,132

Examiner

Mathieu D. Vargot

Applicant(s)/Patent under Reexamination

SAWAISHI ET AL.

Art Unit

1791

SEARCHED

Class	Subclass	Date	Examiner
264	1.33, 106, 107, 328.1		
425	810, 542		
425	193, 385	9/24/2009	MDV

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner